Tektronix®

Testing at the Edge of Innovation

APEC 2026

You're Invited! Booth #511

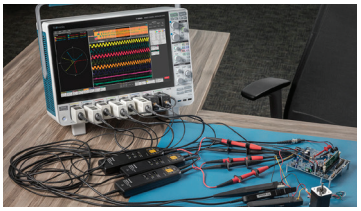
Join us at IEEE Applied Power Electronics Conference, March 22-26, 2026, at the Henry B. Gonzalez Convention Center to experience the latest power testing solutions and connect with our experts. Our team look forward to seeing you there.

Explore Our Showcased Solutions

Enable High Channel Count Parallel Testing

- Mix & match SMU/PSU modules in one mainframe
- Minimize downtime with easy module removal and swapping
- Precisely measure low currents down to picoamps (pA)

Learn more



Correlate 3-Phase Inverter Performance with Robotic Motion

- Perform 3-phase electrical and mechanical measurements to correlate inverter behavior with robotic joint motion
- Enable fast, reliable test setups with robust triggering and phasor diagrams

Learn more

Power the Next Generation of AI Servers with Confidence

- Design, measure, and validate high performance PDNs for AI and datacenters
- Optimize AI and datacenter PDN designs with precise measurement of ultra-low voltage, ultra-high currents and nanosecond scale transient events

Learn more

Simplify Double Pulse Testing for Production and Validation

- Configure turnkey double pulse test systems for production and validation needs
- Test modules and discrete silicon, SiC, and GaN devices on a single flexible platform
- Reduce setup time using reusable test code
- Apply test voltages up to 2 kV, 4.5 kV and 10 kV, and currents up to 6.5 kA

Learn more

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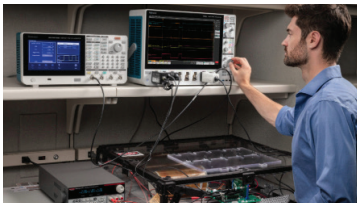

Ensure Accurate, Repeatable Double Pulse Testing for SiC and GaN Designs

- Meet JEDEC and IEC standards using integrated oscilloscope-based double pulse test software
- Measure high bandwidth gate and drain current accurately with isolated shunt probing
- Capture isolated high-side gate-voltage waveforms without compromising measurement integrity

Learn more

Unlock 3-Channel High-power Bidirectional Testing

- Maximize performance with three isolated DC channels, each up to 10 kW, supporting up to 920 V or up to 340 A
- Consolidate multiple testing setups, reducing cost, equipment needs and test time
- Program and get your data quickly with 1 ms response times

Learn more

Hear From Tektronix Experts

Tuesday, March 24, 2026 11:30 AM– 11:55 AM CT | 213	Trends in Wide Bandgap Double Pulse Testing and the Role of AI in Accelerating Automation
Tuesday, March 24, 2026 2:15 PM - 2:45 PM CT | 214A	Fast Out of the Gate: Measuring Gate Driver Performance in SiC Systems
Wednesday, March 25, 2026 2:20 PM - 2:45 PM CT | 210	Automated Calibration Framework for Double Pulse Testing of WBG Devices
Wednesday, March 25, 2026 2:45 PM - 3:10 PM CT | 210	AI-Driven Parasitic Filtering of shunt current measurement for WBG characterisation
Wednesday, March 25, 2026 3:40 PM - 4:05 PM CT | 213	Forced Current Quasistatic C-V Technique for SiC Devices

From everyday measurements to complex challenges—we're ready to help.

Talk to a Tektronix account manager